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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	625
Number of Logic Elements/Cells	5000
Total RAM Bits	169984
Number of I/O	172
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FTBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfxp2-5e-6ft256i

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PFU Blocks

The core of the LatticeXP2 device is made up of logic blocks in two forms, PFUs and PFFs. PFUs can be programmed to perform logic, arithmetic, distributed RAM and distributed ROM functions. PFF blocks can be programmed to perform logic, arithmetic and ROM functions. Except where necessary, the remainder of this data sheet will use the term PFU to refer to both PFU and PFF blocks.

Each PFU block consists of four interconnected slices, numbered Slice 0 through Slice 3, as shown in Figure 2-2. All the interconnections to and from PFU blocks are from routing. There are 50 inputs and 23 outputs associated with each PFU block.



Modes of Operation

Each slice has up to four potential modes of operation: Logic, Ripple, RAM and ROM.

Logic Mode

In this mode, the LUTs in each slice are configured as LUT4s. A LUT4 has 16 possible input combinations. Fourinput logic functions are generated by programming the LUT4. Since there are two LUT4s per slice, a LUT5 can be constructed within one slice. Larger LUTs such as LUT6, LUT7 and LUT8, can be constructed by concatenating two or more slices. Note that a LUT8 requires more than four slices.

Ripple Mode

Ripple mode allows efficient implementation of small arithmetic functions. In ripple mode, the following functions can be implemented by each slice:

- Addition 2-bit
- Subtraction 2-bit
- Add/Subtract 2-bit using dynamic control
- Up counter 2-bit
- Down counter 2-bit
- Up/Down counter with async clear
- Up/Down counter with preload (sync)
- Ripple mode multiplier building block
- Multiplier support
- Comparator functions of A and B inputs
 - A greater-than-or-equal-to B
 - A not-equal-to B
 - A less-than-or-equal-to B

Two carry signals, FCI and FCO, are generated per slice in this mode, allowing fast arithmetic functions to be constructed by concatenating slices.

RAM Mode

In this mode, a 16x4-bit distributed Single Port RAM (SPR) can be constructed using each LUT block in Slice 0 and Slice 2 as a 16x1-bit memory. Slice 1 is used to provide memory address and control signals. A 16x2-bit Pseudo Dual Port RAM (PDPR) memory is created by using one slice as the read-write port and the other companion slice as the read-only port.

The Lattice design tools support the creation of a variety of different size memories. Where appropriate, the software will construct these using distributed memory primitives that represent the capabilities of the PFU. Table 2-3 shows the number of slices required to implement different distributed RAM primitives. For more information on using RAM in LatticeXP2 devices, please see TN1137, <u>LatticeXP2 Memory Usage Guide</u>.

Table 2-3. Number of Slices Required For Implementing Distributed RAM

Number of slices	3 3	

Note: SPR = Single Port RAM, PDPR = Pseudo Dual Port RAM

ROM Mode

ROM mode uses the LUT logic; hence, Slices 0 through 3 can be used in the ROM mode. Preloading is accomplished through the programming interface during PFU configuration.



Routing

There are many resources provided in the LatticeXP2 devices to route signals individually or as busses with related control signals. The routing resources consist of switching circuitry, buffers and metal interconnect (routing) segments.

The inter-PFU connections are made with x1 (spans two PFU), x2 (spans three PFU) or x6 (spans seven PFU) connections. The x1 and x2 connections provide fast and efficient connections in horizontal and vertical directions. The x2 and x6 resources are buffered to allow both short and long connections routing between PFUs.

The LatticeXP2 family has an enhanced routing architecture to produce a compact design. The Diamond design tool takes the output of the synthesis tool and places and routes the design. Generally, the place and route tool is completely automatic, although an interactive routing editor is available to optimize the design.

sysCLOCK Phase Locked Loops (PLL)

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The LatticeXP2 family supports between two and four full featured General Purpose PLLs (GPLL). The architecture of the GPLL is shown in Figure 2-4.

CLKI, the PLL reference frequency, is provided either from the pin or from routing; it feeds into the Input Clock Divider block. CLKFB, the feedback signal, is generated from CLKOP (the primary clock output) or from a user clock pin/logic. CLKFB feeds into the Feedback Divider and is used to multiply the reference frequency.

Both the input path and feedback signals enter the Voltage Controlled Oscillator (VCO) block. The phase and frequency of the VCO are determined from the input path and feedback signals. A LOCK signal is generated by the VCO to indicate that the VCO is locked with the input clock signal.

The output of the VCO feeds into the CLKOP Divider, a post-scalar divider. The duty cycle of the CLKOP Divider output can be fine tuned using the Duty Trim block, which creates the CLKOP signal. By allowing the VCO to operate at higher frequencies than CLKOP, the frequency range of the GPLL is expanded. The output of the CLKOP Divider is passed through the CLKOK Divider, a secondary clock divider, to generate lower frequencies for the CLKOK output. For applications that require even lower frequencies, the CLKOP signal is passed through a divide-by-three divider to produce the CLKOK2 output. The CLKOK2 output is provided for applications that use source synchronous logic. The Phase/Duty Cycle/Duty Trim block is used to adjust the phase and duty cycle of the CLKOP Divider output to generate the CLKOS signal. The phase/duty cycle setting can be pre-programmed or dynamically adjusted.

The clock outputs from the GPLL; CLKOP, CLKOK, CLKOK2 and CLKOS, are fed to the clock distribution network.

For further information on the GPLL please see TN1126, LatticeXP2 sysCLOCK PLL Design and Usage Guide.



MAC sysDSP Element

In this case, the two operands, A and B, are multiplied and the result is added with the previous accumulated value. This accumulated value is available at the output. The user can enable the input and pipeline registers but the output register is always enabled. The output register is used to store the accumulated value. The Accumulators in the DSP blocks in LatticeXP2 family can be initialized dynamically. A registered overflow signal is also available. The overflow conditions are provided later in this document. Figure 2-21 shows the MAC sysDSP element.

Figure 2-21. MAC sysDSP





MULTADDSUBSUM sysDSP Element

In this case, the operands A0 and B0 are multiplied and the result is added/subtracted with the result of the multiplier operation of operands A1 and B1. Additionally the operands A2 and B2 are multiplied and the result is added/ subtracted with the result of the multiplier operation of operands A3 and B3. The result of both addition/subtraction are added in a summation block. The user can enable the input, output and pipeline registers. Figure 2-23 shows the MULTADDSUBSUM sysDSP element.

Figure 2-23. MULTADDSUBSUM



Clock, Clock Enable and Reset Resources

Global Clock, Clock Enable (CE) and Reset (RST) signals from routing are available to every DSP block. From four clock sources (CLK0, CLK1, CLK2, CLK3) one clock is selected for each input register, pipeline register and output



sysIO Recommended Operating Conditions

		V _{CCIO}		V _{REF} (V)				
Standard	Min.	Тур.	Max.	Min.	Тур.	Max.		
LVCMOS33 ²	3.135	3.3	3.465	—				
LVCMOS25 ²	2.375	2.5	2.625	—				
LVCMOS18	1.71	1.8	1.89	—	—	—		
LVCMOS15	1.425	1.5	1.575	—				
LVCMOS12 ²	1.14	1.2	1.26	—				
LVTTL33 ²	3.135	3.3	3.465	—	—	—		
PCI33	3.135	3.3	3.465	—		—		
SSTL18_I ² , SSTL18_II ²	1.71	1.8	1.89	0.833	0.9	0.969		
SSTL25_I ² , SSTL25_II ²	2.375	2.5	2.625	1.15	1.25	1.35		
SSTL33_I ² , SSTL33_II ²	3.135	3.3	3.465	1.3	1.5	1.7		
HSTL15_l ²	1.425	1.5	1.575	0.68	0.75	0.9		
HSTL18_I ² , HSTL18_II ²	1.71	1.8	1.89	0.816	0.9	1.08		
LVDS25 ²	2.375	2.5	2.625	—				
MLVDS251	2.375	2.5	2.625	—				
LVPECL33 ^{1, 2}	3.135	3.3	3.465	—				
BLVDS25 ^{1, 2}	2.375	2.5	2.625	—				
RSDS ^{1, 2}	2.375	2.5	2.625	—				
SSTL18D_I ² , SSTL18D_II ²	1.71	1.8	1.89	—	—	—		
SSTL25D_ I ² , SSTL25D_II ²	2.375	2.5	2.625	—	—	—		
SSTL33D_ I ² , SSTL33D_ II ²	3.135	3.3	3.465	—	—	—		
HSTL15D_ I ²	1.425	1.5	1.575	—	—	—		
HSTL18D_ I ² , HSTL18D_ II ²	1.71	1.8	1.89	_	—	—		

Over Recommended Operating Conditions

1. Inputs on chip. Outputs are implemented with the addition of external resistors. 2. Input on this standard does not depend on the value of V_{CCIO} .



Table 3-1. LVDS25E DC Conditions

Parameter	Description	Typical	Units
V _{CCIO}	Output Driver Supply (+/-5%)	2.50	V
Z _{OUT}	Driver Impedance	20	Ω
R _S	Driver Series Resistor (+/-1%)	158	Ω
R _P	Driver Parallel Resistor (+/-1%)	140	Ω
R _T	Receiver Termination (+/-1%)	100	Ω
V _{OH}	Output High Voltage (after R _P)	1.43	V
V _{OL}	Output Low Voltage (after R _P)	1.07	V
V _{OD}	Output Differential Voltage (After R _P)	0.35	V
V _{CM}	Output Common Mode Voltage	1.25	V
Z _{BACK}	Back Impedance	100.5	Ω
I _{DC}	DC Output Current	6.03	mA

LVCMOS33D

All I/O banks support emulated differential I/O using the LVCMOS33D I/O type. This option, along with the external resistor network, provides the system designer the flexibility to place differential outputs on an I/O bank with 3.3V VCCIO. The default drive current for LVCMOS33D output is 12mA with the option to change the device strength to 4mA, 8mA, 16mA or 20mA. Follow the LVCMOS33 specifications for the DC characteristics of the LVCMOS33D.



BLVDS

The LatticeXP2 devices support the BLVDS standard. This standard is emulated using complementary LVCMOS outputs in conjunction with a parallel external resistor across the driver outputs. BLVDS is intended for use when multi-drop and bi-directional multi-point differential signaling is required. The scheme shown in Figure 3-2 is one possible solution for bi-directional multi-point differential signals.





Table 3-2. BLVDS DC Conditions¹

		Тур		
Parameter	Description	Ζο = 45 Ω	Ζο = 90 Ω	Units
V _{CCIO}	Output Driver Supply (+/- 5%)	2.50	2.50	V
Z _{OUT}	Driver Impedance	10.00	10.00	Ω
R _S	Driver Series Resistor (+/- 1%)	90.00	90.00	Ω
R _{TL}	Driver Parallel Resistor (+/- 1%)	45.00	90.00	Ω
R _{TR}	Receiver Termination (+/- 1%)	45.00	90.00	Ω
V _{OH}	Output High Voltage (After R _{TL})	1.38	1.48	V
V _{OL}	Output Low Voltage (After R _{TL})	1.12	1.02	V
V _{OD}	Output Differential Voltage (After R _{TL})	0.25	0.46	V
V _{CM}	Output Common Mode Voltage	1.25	1.25	V
I _{DC}	DC Output Current	11.24	10.20	mA

Over Recommended Operating Conditions

1. For input buffer, see LVDS table.



RSDS

The LatticeXP2 devices support differential RSDS standard. This standard is emulated using complementary LVC-MOS outputs in conjunction with a parallel resistor across the driver outputs. The RSDS input standard is supported by the LVDS differential input buffer. The scheme shown in Figure 3-4 is one possible solution for RSDS standard implementation. Resistor values in Figure 3-4 are industry standard values for 1% resistors.



Figure 3-4. RSDS (Reduced Swing Differential Standard)

Table 3-4. RSDS DC Conditions¹

Parameter	Description	Typical	Units
V _{CCIO}	Output Driver Supply (+/-5%)	2.50	V
Z _{OUT}	Driver Impedance	20	Ω
R _S	Driver Series Resistor (+/-1%)	294	Ω
R _P	Driver Parallel Resistor (+/-1%)	121	Ω
R _T	Receiver Termination (+/-1%)	100	Ω
V _{OH}	Output High Voltage (After R _P)	1.35	V
V _{OL}	Output Low Voltage (After R _P)	1.15	V
V _{OD}	Output Differential Voltage (After R _P)	0.20	V
V _{CM}	Output Common Mode Voltage	1.25	V
Z _{BACK}	Back Impedance	101.5	Ω
I _{DC}	DC Output Current	3.66	mA

Over Recommended Operating Conditions

1. For input buffer, see LVDS table.



Typical Building Block Function Performance¹

Pin-to-Pin Performance (LVCMOS25 12mA Drive)

Function	-7 Timing	Units
Basic Functions		
16-bit Decoder	4.4	ns
32-bit Decoder	5.2	ns
64-bit Decoder	5.6	ns
4:1 MUX	3.7	ns
8:1 MUX	3.9	ns
16:1 MUX	4.3	ns
32:1 MUX	4.5	ns

Register-to-Register Performance

Function	-7 Timing	Units
Basic Functions		
16-bit Decoder	521	MHz
32-bit Decoder	537	MHz
64-bit Decoder	484	MHz
4:1 MUX	744	MHz
8:1 MUX	678	MHz
16:1 MUX	616	MHz
32:1 MUX	529	MHz
8-bit Adder	570	MHz
16-bit Adder	507	MHz
64-bit Adder	293	MHz
16-bit Counter	541	MHz
32-bit Counter	440	MHz
64-bit Counter	321	MHz
64-bit Accumulator	261	MHz
Embedded Memory Functions		
512x36 Single Port RAM, EBR Output Registers	315	MHz
1024x18 True-Dual Port RAM (Write Through or Normal, EBR Output Registers)	315	MHz
1024x18 True-Dual Port RAM (Write Through or Normal, PLC Output Registers)	231	MHz
Distributed Memory Functions		
16x4 Pseudo-Dual Port RAM (One PFU)	760	MHz
32x2 Pseudo-Dual Port RAM	455	MHz
64x1 Pseudo-Dual Port RAM	351	MHz
DSP Functions		
18x18 Multiplier (All Registers)	342	MHz
9x9 Multiplier (All Registers)	342	MHz
36x36 Multiply (All Registers)	330	MHz
18x18 Multiply/Accumulate (Input and Output Registers)	218	MHz
18x18 Multiply-Add/Sub-Sum (All Registers)	292	MHz



Register-to-Register Performance (Continued)

Function	-7 Timing	Units
DSP IP Functions		
16-Tap Fully-Parallel FIR Filter	198	MHz
1024-pt FFT	221	MHz
8X8 Matrix Multiplication	196	MHz

1. These timing numbers were generated using the ispLEVER design tool. Exact performance may vary with device, design and tool version. The tool uses internal parameters that have been characterized but are not tested on every device.

Derating Timing Tables

Logic timing provided in the following sections of this data sheet and the Diamond design tools are worst case numbers in the operating range. Actual delays at nominal temperature and voltage for best case process, can be much better than the values given in the tables. The Diamond design tool can provide logic timing numbers at a particular temperature and voltage.



LatticeXP2 External Switching Characteristics

			-	7	-	6	-	5	
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
General I/O Pir	n Parameters (using Primary Clo	ck without F	PLL)1						
		XP2-5		3.80	_	4.20	_	4.60	ns
		XP2-8		3.80		4.20		4.60	ns
t _{CO}	Register	XP2-17		3.80	_	4.20	_	4.60	ns
		XP2-30		4.00	_	4.40	_	4.90	ns
		XP2-40		4.00	_	4.40		4.90	ns
		XP2-5	0.00		0.00	—	0.00		ns
		XP2-8	0.00	_	0.00	—	0.00	_	ns
t _{SU}	Register	XP2-17	0.00	_	0.00	—	0.00	_	ns
		XP2-30	0.00	_	0.00	—	0.00	_	ns
		XP2-40	0.00		0.00	—	0.00		ns
		XP2-5	1.40	_	1.70	—	1.90	_	ns
		XP2-8	1.40	_	1.70	—	1.90	_	ns
t _H	Register	XP2-17	1.40	_	1.70	—	1.90	_	ns
		XP2-30	1.40		1.70	—	1.90		ns
		XP2-40	1.40	_	1.70	—	1.90	_	ns
	Clock to Data Setup - PIO Input Register with Data Input Delay	XP2-5	1.40	_	1.70	—	1.90	_	ns
		XP2-8	1.40	_	1.70	—	1.90	_	ns
t _{SU_DEL}		XP2-17	1.40	_	1.70	—	1.90	_	ns
		XP2-30	1.40		1.70	_	1.90		ns
		XP2-40	1.40	_	1.70	—	1.90	_	ns
		XP2-5	0.00	_	0.00	—	0.00	_	ns
	Clock to Data Hold - PIO Input Register with Input Data Delay	XP2-8	0.00	_	0.00	—	0.00	_	ns
t _{H_DEL}		XP2-17	0.00	_	0.00	—	0.00	_	ns
		XP2-30	0.00		0.00	—	0.00		ns
		XP2-40	0.00		0.00	—	0.00		ns
f _{MAX_IO}	Clock Frequency of I/O and PFU Register	XP2	_	420	_	357	_	311	MHz
General I/O Pir	n Parameters (using Edge Clock	without PLL	.) ¹						
		XP2-5	_	3.20	—	3.60	—	3.90	ns
		XP2-8		3.20	_	3.60	_	3.90	ns
t _{COE}	Clock to Output - PIO Output Register	XP2-17		3.20		3.60		3.90	ns
		XP2-30		3.20	_	3.60		3.90	ns
		XP2-40		3.20	_	3.60	_	3.90	ns
		XP2-5	0.00	_	0.00	—	0.00	_	ns
		XP2-8	0.00		0.00	_	0.00		ns
t _{SUE}	Register	XP2-17	0.00	—	0.00	—	0.00	—	ns
		XP2-30	0.00		0.00	—	0.00		ns
		XP2-40	0.00		0.00		0.00		ns

Over Recommended Operating Conditions



EBR Timing Diagrams





Note: Input data and address are registered at the positive edge of the clock and output data appears after the positive edge of the clock.

Figure 3-7. Read/Write Mode with Input and Output Registers









Note: Input data and address are registered at the positive edge of the clock and output data appears after the positive edge of the clock.



LatticeXP2 Family Timing Adders^{1, 2, 3, 4} (Continued)

Buffer Type	Description	-7	-6	-5	Units
HSTL15_I	HSTL_15 class I 4mA drive	0.32	0.69	1.06	ns
HSTL15D_I	Differential HSTL 15 class I 4mA drive	0.32	0.69	1.06	ns
SSTL33_I	SSTL_3 class I	-0.25	0.05	0.35	ns
SSTL33_II	SSTL_3 class II	-0.31	-0.02	0.27	ns
SSTL33D_I	Differential SSTL_3 class I	-0.25	0.05	0.35	ns
SSTL33D_II	Differential SSTL_3 class II	-0.31	-0.02	0.27	ns
SSTL25_I	SSTL_2 class I 8mA drive	-0.25	0.02	0.30	ns
SSTL25_II	SSTL_2 class II 16mA drive	-0.28	0.00	0.28	ns
SSTL25D_I	Differential SSTL_2 class I 8mA drive	-0.25	0.02	0.30	ns
SSTL25D_II	Differential SSTL_2 class II 16mA drive	-0.28	0.00	0.28	ns
SSTL18_I	SSTL_1.8 class I	-0.17	0.13	0.43	ns
SSTL18_II	SSTL_1.8 class II 8mA drive	-0.18	0.12	0.42	ns
SSTL18D_I	Differential SSTL_1.8 class I	-0.17	0.13	0.43	ns
SSTL18D_II	Differential SSTL_1.8 class II 8mA drive	-0.18	0.12	0.42	ns
LVTTL33_4mA	LVTTL 4mA drive	-0.37	-0.05	0.26	ns
LVTTL33_8mA	LVTTL 8mA drive	-0.45	-0.18	0.10	ns
LVTTL33_12mA	LVTTL 12mA drive	-0.52	-0.24	0.04	ns
LVTTL33_16mA	LVTTL 16mA drive	-0.43	-0.14	0.14	ns
LVTTL33_20mA	LVTTL 20mA drive	-0.46	-0.18	0.09	ns
LVCMOS33_4mA	LVCMOS 3.3 4mA drive, fast slew rate	-0.37	-0.05	0.26	ns
LVCMOS33_8mA	LVCMOS 3.3 8mA drive, fast slew rate	-0.45	-0.18	0.10	ns
LVCMOS33_12mA	LVCMOS 3.3 12mA drive, fast slew rate	-0.52	-0.24	0.04	ns
LVCMOS33_16mA	LVCMOS 3.3 16mA drive, fast slew rate	-0.43	-0.14	0.14	ns
LVCMOS33_20mA	LVCMOS 3.3 20mA drive, fast slew rate	-0.46	-0.18	0.09	ns
LVCMOS25_4mA	LVCMOS 2.5 4mA drive, fast slew rate	-0.42	-0.15	0.13	ns
LVCMOS25_8mA	LVCMOS 2.5 8mA drive, fast slew rate	-0.48	-0.21	0.05	ns
LVCMOS25_12mA	LVCMOS 2.5 12mA drive, fast slew rate	0.00	0.00	0.00	ns
LVCMOS25_16mA	LVCMOS 2.5 16mA drive, fast slew rate	-0.45	-0.18	0.08	ns
LVCMOS25_20mA	LVCMOS 2.5 20mA drive, fast slew rate	-0.49	-0.22	0.04	ns
LVCMOS18_4mA	LVCMOS 1.8 4mA drive, fast slew rate	-0.46	-0.18	0.10	ns
LVCMOS18_8mA	LVCMOS 1.8 8mA drive, fast slew rate	-0.52	-0.25	0.02	ns
LVCMOS18_12mA	LVCMOS 1.8 12mA drive, fast slew rate	-0.56	-0.30	-0.03	ns
LVCMOS18_16mA	LVCMOS 1.8 16mA drive, fast slew rate	-0.50	-0.24	0.03	ns
LVCMOS15_4mA	LVCMOS 1.5 4mA drive, fast slew rate	-0.45	-0.17	0.11	ns
LVCMOS15_8mA	LVCMOS 1.5 8mA drive, fast slew rate	-0.53	-0.26	0.00	ns
LVCMOS12_2mA	LVCMOS 1.2 2mA drive, fast slew rate	-0.46	-0.19	0.08	ns
LVCMOS12_6mA	LVCMOS 1.2 6mA drive, fast slew rate	-0.55	-0.29	-0.02	ns
LVCMOS33_4mA	LVCMOS 3.3 4mA drive, slow slew rate	0.98	1.41	1.84	ns
LVCMOS33_8mA	LVCMOS 3.3 8mA drive, slow slew rate	0.74	1.16	1.58	ns
LVCMOS33_12mA	LVCMOS 3.3 12mA drive, slow slew rate	0.56	0.97	1.38	ns
LVCMOS33_16mA	LVCMOS 3.3 16mA drive, slow slew rate	0.77	1.19	1.61	ns
LVCMOS33_20mA	LVCMOS 3.3 20mA drive, slow slew rate	0.57	0.98	1.40	ns

Over Recommended Operating Conditions



LatticeXP2 sysCONFIG Port Timing Specifications

Parameter	Description	Min	Max	Units
sysCONFIG PO	R, Initialization and Wake Up			
t _{ICFG}	Minimum Vcc to INITN High	_	50	ms
t _{VMC}	Time from t _{ICFG} to valid Master CCLK	_	2	μs
t _{PRGMRJ}	PROGRAMN Pin Pulse Rejection	_	12	ns
t _{PRGM}	PROGRAMN Low Time to Start Configuration	50	—	ns
t _{DINIT} 1	PROGRAMN High to INITN High Delay	_	1	ms
t _{DPPINIT}	Delay Time from PROGRAMN Low to INITN Low	_	50	ns
t _{DPPDONE}	Delay Time from PROGRAMN Low to DONE Low	_	50	ns
t _{IODISS}	User I/O Disable from PROGRAMN Low	_	35	ns
t _{IOENSS}	User I/O Enabled Time from CCLK Edge During Wake-up Sequence	_	25	ns
t _{MWC}	Additional Wake Master Clock Signals after DONE Pin High	0	—	Cycles
sysCONFIG SP	I Port (Master)			
t _{CFGX}	INITN High to CCLK Low	_	1	μs
t _{CSSPI}	INITN High to CSSPIN Low	_	2	μs
t _{CSCCLK}	CCLK Low before CSSPIN Low	0	—	ns
t _{SOCDO}	CCLK Low to Output Valid	_	15	ns
t _{CSPID}	CSSPIN[0:1] Low to First CCLK Edge Setup Time	2cyc	600+6cyc	ns
f _{MAXSPI}	Max CCLK Frequency	—	20	MHz
t _{SUSPI}	SOSPI Data Setup Time Before CCLK	7	—	ns
t _{HSPI}	SOSPI Data Hold Time After CCLK	10	—	ns
sysCONFIG SP	I Port (Slave)			
f _{MAXSPIS}	Slave CCLK Frequency	—	25	MHz
t _{RF}	Rise and Fall Time	50	—	mV/ns
t _{STCO}	Falling Edge of CCLK to SOSPI Active	—	20	ns
t _{STOZ}	Falling Edge of CCLK to SOSPI Disable	—	20	ns
t _{STSU}	Data Setup Time (SISPI)	8	—	ns
t _{STH}	Data Hold Time (SISPI)	10	—	ns
t _{sтскн}	CCLK Clock Pulse Width, High	0.02	200	μs
t _{STCKL}	CCLK Clock Pulse Width, Low	0.02	200	μs
t _{STVO}	Falling Edge of CCLK to Valid SOSPI Output		20	ns
t _{SCS}	CSSPISN High Time	25	—	ns
t _{SCSS}	CSSPISN Setup Time	25	—	ns
t _{SCSH}	CSSPISN Hold Time	25	—	ns

Over Recommended Operating Conditions

1. Re-toggling the PROGRAMN pin is not permitted until the INITN pin is high. Avoid consecutive toggling of PROGRAMN.



FlashBAK Time (from EBR to Flash)

Over Recommended Operating Conditions

Device	EBR Density (Bits)	Time (Typ.)	Units
XP2-5	166K	1.5	S
XP2-8	221K	1.5	S
XP2-17	276K	1.5	S
XP2-30	387K	2.0	S
XP2-40	885K	3.0	S

JTAG Port Timing Specifications

Over Recommended Operating Conditions

Symbol	Parameter	Min.	Max.	Units
f _{MAX}	TCK Clock Frequency	—	25	MHz
t _{BTCP}	TCK [BSCAN] clock pulse width	40	—	ns
t _{BTCPH}	TCK [BSCAN] clock pulse width high	20	—	ns
t _{BTCPL}	TCK [BSCAN] clock pulse width low	20	—	ns
t _{BTS}	TCK [BSCAN] setup time	8	—	ns
t _{BTH}	TCK [BSCAN] hold time	10	—	ns
t _{BTRF}	TCK [BSCAN] rise/fall time	50	—	mV/ns
t _{BTCO}	TAP controller falling edge of clock to valid output	—	10	ns
t _{BTCODIS}	TAP controller falling edge of clock to valid disable	—	10	ns
t _{BTCOEN}	TAP controller falling edge of clock to valid enable	—	10	ns
t _{BTCRS}	BSCAN test capture register setup time	8	—	ns
t _{BTCRH}	BSCAN test capture register hold time	25	—	ns
t _{BUTCO}	BSCAN test update register, falling edge of clock to valid output	—	25	ns
t _{BTUODIS}	BSCAN test update register, falling edge of clock to valid disable	—	25	ns
t _{BTUPOEN}	BSCAN test update register, falling edge of clock to valid enable	_	25	ns



Switching Test Conditions

Figure 3-11 shows the output test load that is used for AC testing. The specific values for resistance, capacitance, voltage, and other test conditions are shown in Table 3-6.

Figure 3-11. Output Test Load, LVTTL and LVCMOS Standards



*CL Includes Test Fixture and Probe Capacitance

 Table 3-6. Test Fixture Required Components, Non-Terminated Interfaces

Test Condition	R ₁	R ₂	CL	Timing Ref.	V _T
				LVCMOS 3.3 = 1.5V	
LVTTL and other LVCMOS settings (L -> H, H -> L)		œ	0pF	LVCMOS 2.5 = $V_{CCIO}/2$	
	∞			LVCMOS 1.8 = V _{CCIO} /2	
				LVCMOS 1.5 = $V_{CCIO}/2$	_
				LVCMOS 1.2 = V _{CCIO} /2	_
LVCMOS 2.5 I/O (Z -> H)	x	1MΩ		V _{CCIO} /2	
LVCMOS 2.5 I/O (Z -> L)	1MΩ	∞		V _{CCIO} /2	V _{CCIO}
LVCMOS 2.5 I/O (H -> Z)	8	100		V _{OH} - 0.10	
LVCMOS 2.5 I/O (L -> Z)	100	∞		V _{OL} + 0.10	V _{CCIO}

Note: Output test conditions for all other interfaces are determined by the respective standards.



Lead-Free Packaging

Commercial

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-5E-5MN132C	1.2V	-5	Lead-Free csBGA	132	COM	5
LFXP2-5E-6MN132C	1.2V	-6	Lead-Free csBGA	132	COM	5
LFXP2-5E-7MN132C	1.2V	-7	Lead-Free csBGA	132	COM	5
LFXP2-5E-5TN144C	1.2V	-5	Lead-Free TQFP	144	COM	5
LFXP2-5E-6TN144C	1.2V	-6	Lead-Free TQFP	144	COM	5
LFXP2-5E-7TN144C	1.2V	-7	Lead-Free TQFP	144	COM	5
LFXP2-5E-5QN208C	1.2V	-5	Lead-Free PQFP	208	COM	5
LFXP2-5E-6QN208C	1.2V	-6	Lead-Free PQFP	208	COM	5
LFXP2-5E-7QN208C	1.2V	-7	Lead-Free PQFP	208	COM	5
LFXP2-5E-5FTN256C	1.2V	-5	Lead-Free ftBGA	256	COM	5
LFXP2-5E-6FTN256C	1.2V	-6	Lead-Free ftBGA	256	COM	5
LFXP2-5E-7FTN256C	1.2V	-7	Lead-Free ftBGA	256	COM	5

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-8E-5MN132C	1.2V	-5	Lead-Free csBGA	132	COM	8
LFXP2-8E-6MN132C	1.2V	-6	Lead-Free csBGA	132	COM	8
LFXP2-8E-7MN132C	1.2V	-7	Lead-Free csBGA	132	COM	8
LFXP2-8E-5TN144C	1.2V	-5	Lead-Free TQFP	144	COM	8
LFXP2-8E-6TN144C	1.2V	-6	Lead-Free TQFP	144	COM	8
LFXP2-8E-7TN144C	1.2V	-7	Lead-Free TQFP	144	COM	8
LFXP2-8E-5QN208C	1.2V	-5	Lead-Free PQFP	208	COM	8
LFXP2-8E-6QN208C	1.2V	-6	Lead-Free PQFP	208	COM	8
LFXP2-8E-7QN208C	1.2V	-7	Lead-Free PQFP	208	COM	8
LFXP2-8E-5FTN256C	1.2V	-5	Lead-Free ftBGA	256	COM	8
LFXP2-8E-6FTN256C	1.2V	-6	Lead-Free ftBGA	256	COM	8
LFXP2-8E-7FTN256C	1.2V	-7	Lead-Free ftBGA	256	COM	8

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-17E-5QN208C	1.2V	-5	Lead-Free PQFP	208	COM	17
LFXP2-17E-6QN208C	1.2V	-6	Lead-Free PQFP	208	COM	17
LFXP2-17E-7QN208C	1.2V	-7	Lead-Free PQFP	208	COM	17
LFXP2-17E-5FTN256C	1.2V	-5	Lead-Free ftBGA	256	COM	17
LFXP2-17E-6FTN256C	1.2V	-6	Lead-Free ftBGA	256	COM	17
LFXP2-17E-7FTN256C	1.2V	-7	Lead-Free ftBGA	256	COM	17
LFXP2-17E-5FN484C	1.2V	-5	Lead-Free fpBGA	484	COM	17
LFXP2-17E-6FN484C	1.2V	-6	Lead-Free fpBGA	484	COM	17
LFXP2-17E-7FN484C	1.2V	-7	Lead-Free fpBGA	484	COM	17



Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-17E-5QN208I	1.2V	-5	Lead-Free PQFP	208	IND	17
LFXP2-17E-6QN208I	1.2V	-6	Lead-Free PQFP	208	IND	17
LFXP2-17E-5FTN256I	1.2V	-5	Lead-Free ftBGA	256	IND	17
LFXP2-17E-6FTN256I	1.2V	-6	Lead-Free ftBGA	256	IND	17
LFXP2-17E-5FN484I	1.2V	-5	Lead-Free fpBGA	484	IND	17
LFXP2-17E-6FN484I	1.2V	-6	Lead-Free fpBGA	484	IND	17

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-30E-5FTN256I	1.2V	-5	Lead-Free ftBGA	256	IND	30
LFXP2-30E-6FTN256I	1.2V	-6	Lead-Free ftBGA	256	IND	30
LFXP2-30E-5FN484I	1.2V	-5	Lead-Free fpBGA	484	IND	30
LFXP2-30E-6FN484I	1.2V	-6	Lead-Free fpBGA	484	IND	30
LFXP2-30E-5FN672I	1.2V	-5	Lead-Free fpBGA	672	IND	30
LFXP2-30E-6FN672I	1.2V	-6	Lead-Free fpBGA	672	IND	30

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-40E-5FN484I	1.2V	-5	Lead-Free fpBGA	484	IND	40
LFXP2-40E-6FN484I	1.2V	-6	Lead-Free fpBGA	484	IND	40
LFXP2-40E-5FN672I	1.2V	-5	Lead-Free fpBGA	672	IND	40
LFXP2-40E-6FN672I	1.2V	-6	Lead-Free fpBGA	672	IND	40